**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**<u>Listing of Claims</u>:**

1. (Original) Method for automatically developing a testing program of a tester, comprising steps of:

    establishing an intellectual property comprising a tester library, a tester resource installation configuration and a testing strategy;

    integrating said intellectual property with a product target specification, an error code list and a program transfer rule check; and

    automatically developing a source code prototype of said testing program.

2. (Original) The method according to claim 1, wherein said tester is one of a digital tester and an analog tester.

3. (Original) The method according to claim 1, wherein said tester library comprises pattern file formats and source code prototypes for a plurality of known testers.

4. (Original) The method according to claim 1, wherein said tester resource installation configuration comprises Pin electronics (PE) specification and maximum channels, a precision measurement unit (PMU) specifications, a device power supplies (DPS) specification, a time measurement unit (TMU) specification, a vector memory size specification, a system clock rate specification and an analog channel specification.

5. (Currently amended) The method according to claim 1, wherein said testing strategy comprises a testing item selected from one of <u>a testing item of</u> a logical product and <u>a</u> <u>testing item of</u> an analog product.

6. (Original) The method according to claim 5, wherein said testing item of said logical product is one selected from a group consisting of continuity test, drive/sink current test,

power dissipation test, IDDQ test, input leakage current test, function pattern test and AC characteristic test.

7 (Original) The method according to claim 5, wherein said testing item of said analog product is one selected from a group consisting of ADC/DAC's SNR test, THD test, Jitter/Skew test, crosstalk test, eye diagram test and frequency response test.